## Applicant(s)/Patent Under Application/Control No. Reexamination 10/658,175 CHANG ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1624 Kahsay Habte, Ph. D. **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name MM-YYYY Country Code-Number-Kind Code US-Α US-В US-С US-D Ε US-F US-US-G US-Н USı US-J K US-US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Classification Name Country Country Code-Number-Kind Code MM-YYYY Ν О Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) Allessandro, et al. Ric. Sci, Rend., Sez. A (1965), 8(6), 1537-9. W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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